MSKSEMI















ESD

TVS

TSS

MOV

GDT

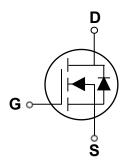
PLED

Broduct data sheet





SOT-23-3L



Features

- 20 V, 3A, RDS(ON) = $50m\Omega$ @ VGS = 4.5V
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Hend- Held Instruments

BVDSS	RDSON	ID
20V	50mΩ	3A

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
Vds	Drain- Source Voltage	20	V
Vgs	Gate-Source Voltage	±10	V
	Drain Current - Continuous (T _C =250)	3	А
lo	Drain Current - Continuous (Tc=1000)	2.5	А
Ірм	Drain Current – Pulsed ¹	16	А
_	Power Dissipation (Tc=250)	1.56	W
PD	Power Dissipation – Derate above 250	0.012	W/ C
Тѕтс	Storage Temperature Range	-55 to 150	С
TJ	Operating Junction Temperature Range	-55 to 150	С

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		80	C/ W



Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BVDSS	Drain- Source Breakdown Voltage	Vgs=0V , Ip=250uA	20			V
△BVDSS/△TJ	BV _{DSS} Temperature Coefficient	Reference to 250 , I _D =1mA		0.02		V/ C
	Drain-Source Leakage Current	V _{DS} =20V , V _{GS} =0V , T _J =250			1	uд
Ipss		V _{DS} =16V , V _{GS} =0V , T _J =125C			10	uĄ
Igss	Gate- Source Leakage Current	V _{GS=} ±10V , V _{DS} =0V			±100	nĄ

On Characteristics

R _{DS(ON)} Sta	Static Drain-Source On-Resistance	V _{GS} =4.5V , I _D =2A		50	60	mΩ	
		Vgs=2.5V , Ip=1A		55	70	1162	
V _{GS(th)}	Gate Threshold Voltage	\\	0.4	0.7	1	V	
△VGS(th)	V _{GS(th)} Temperature Coefficient	Vgs=Vps , In =250uA		2		mV/ C	
gfs	Forward Transconductance	V _{DS} =10V , I _S =2A		4.4		S	

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2, 3}		 3.6	
Qgs	Gate-Source Charge ^{2, 3}	V _{DS} =10V , V _{GS} =4.5V , I _D =1A	 0.38	 nC
Qgd	Gate-Drain Charge ^{2, 3}		 0.6	
T _{d(on)}	Turn-On Delay Time ^{2, 3}		 1.8	
Tr	Rise Time ^{2, 3}	V_{DD} =10V , V_{GS} =4.5V , R_{G} =25 Ω	 5.6	 ns
T _{d(off)}	Turn-Off Delay Time ^{2, 3}	I _D =1A	 11.3	 113
Tf	Fall Time ^{2 , 3}		 3.2	
Ciss	Input Capacitance		 180	
Coss	Output Capacitance	V _{DS} =15V , V _{GS} =0V , F=1MHz	 32	 PF
Crss	Reverse Transfer Capacitance		 26	

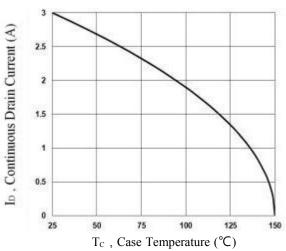
Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V . Force Current			3	Α
lsм	Pulsed Source Current	TVG-VD-0V, FOICE CUITEIIL			6	Α
VsD	Diode Forward Voltage	Vgs=0V , Is=1A , TJ=250			1.2	V

Note:

- 1 . Repetitive Rating : Pulsed width limited by maximum junction temperature .
- 2 . The data tested by pulsed , pulse width \leq 3 0 0 us , duty cycle \leq 2 % .
- 3 . Essentially independent of operating temperature.





Continuous Drain Current vs. T_c Fig. 1

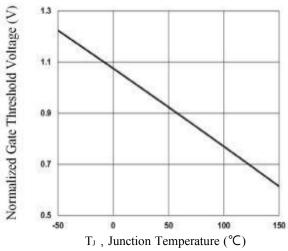


Fig. 3 Normalized V_{th} vs.

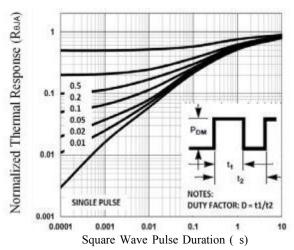


Fig. 5 Normalized Transient Impedance

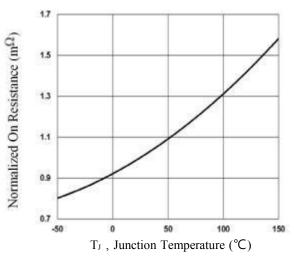


Fig. 2 Normalized RDSON vs. T_J

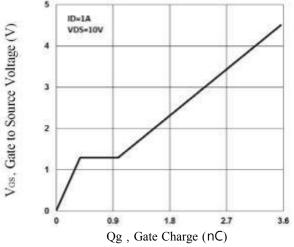
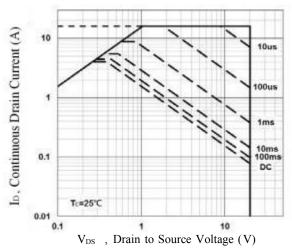
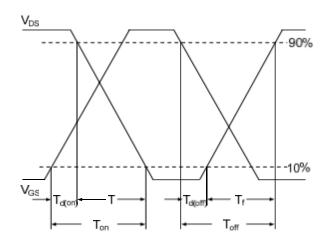


Fig. 4 Gate Charge Waveform



Maximum Safe Operation Area Fig. 6





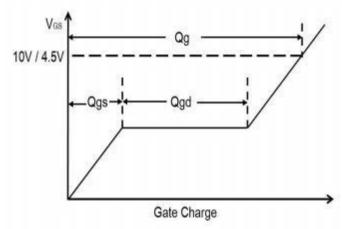
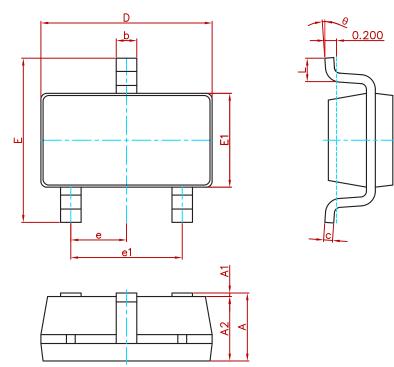


Fig. 7 Switching Time Waveform

Fig. 8 Gate Charge Waveform

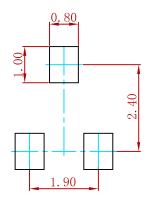


PACKAGE MECHANICAL DATA



Symbol	Dimensions In	Dimensions In Millimeters		s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(BSC)		0.037((BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
AO3414	SOT-23-3L	3000



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